Sheet 1 (A) of 1 SUBSTITUTE ORM PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. PATENT AND TRADEMARK OFFICE SSIT-114 10/711,649 **APPLICANT** INFORMATION DISCLOSURE STATEMENT BY APPLICANT Kawamura et al. (Use several sheets if necessary) **FILING DATE GROUP** 09/29/2004 1756 U.S. PATENT DOCUMENTS ISSUE FILING DATE **EXAMINER** IF APPROPRIATE **PATENTEE CLASS SUBCLASS** PATENT NUMBER DATE INITIAL M NJ 6 5 9 6 0 8 07/22/2003 DeYoung et al. 134 09/13/2001 A.A A.B A.C A.D A.E . . . A.F A.G A.H A.I A.J A.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **TRANSLATION COUNTRY OR PUBLICATION** DOCUMENT **SUBCLASS** (YES/NO) NUMBER DATE PATENT OFFICE **CLASS** MDIT **Abstract Only** H01L 21/68 JP 10/09/1992 A.L JP 4-284648 H01L 21/68 **Abstract Only** J۶ 05/22/1987 A,M JP 62-111442 JP **B23Q** 3/08 **Abstract Only** JP 63-256326 10/24/1988 A.N A.O A.P A.Q OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) Cotte et al., Process and Apparatus for Contacting a Precision Surface with Liquid or Supercritical Carbon Dioxide, US A.R MDH 2003/0196679 A1; Publication Date 10/23/2003; Filing Date 04/18/2002; U.S. Class 134/1 A.S A.T **EXAMINER** DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not in conformance. Draw line through citation only if not in conformance and not considered.

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		B.D	4	3	6	7	1	4	0	01/04/1983	Wilson		210	110		10/30/1980
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		D.C	4	8	6	5	0	6	1	09/12/1989	Fowler et al.		134	108		07/22/1983
		D.D	4	8	7	7	5	3	0	10/31/1989	Moses		210	511		02/29/1988
		D.E	4	8	7	9	0	0	4	11/07/1989	Oesch et al.		203	89		05/04/1988
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Sheet 5 (E) of 28

SUBSTIT		FORM P	TO-	144	9						ENT OF COMMERCE RADEMARK OFFICE	ATTY. SSIT-1	DOCKET NO 14).	SERIA 10/711	
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MDI	17	E.A	4	9	4	4	8	3	7	07/31/1990	Nishikawa et al.	-	156	646		02/28/1989
		E.B	4	9	5	1	6	0	1	08/28/1990	Maydan et al.		118	719		06/23/1989
		E.C	4	9	6	0	1	4	0	10/02/1990	Ishijima et al.		134	31		11/27/1985
		E.D	4	9	8	3	2	2	3	01/08/1991	Gessner		134	25.4		10/24/1989
		E.E	5	0	1	1	5	4	2	04/30/1991	Weil		134	38		07/21/1988
		E.F 5 0 1 3 3 6 6 05/07/1991 Jackson et al. 134 1 12/07/1988 E.G 5 0 4 4 8 7 1 09/03/1991 Davis et al. 414 786 01/13/1988 E.H 5 0 6 2 7 7 0 11/05/1991 Story et al. 417 46 08/11/1989														12/07/1988
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MD	11		Flu	ld S	olu	tion,	Ch	emic	al Pi	nysics Letters,	pp. 585-588, May 22, 1	998.				
		E.S	K We	Jack estw	(SO	n et I, NJ	ai., , pp	<u>Surf</u> . 87	actar -120,	nts and Micron , Spring 1998.	nulsions in Supercritical	<u>Fluids,</u> S	upercritical F	luid Clea	ning, No	yes Publications,
V		E.T	M. 199		szc	wski	, Pr	oduc	ction	of Metal and S	Semiconductor Nanopari	ticles in P	olymer Syst	ems, Poli	mery, pp	o. 65-73, February
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Sheet 6 (F) of 28

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m	DH	F.A	5	1	4	3	1	0	3	09/01/1992	Basso et al.		134	98.1		01/04/1991
	<u> </u>	F.B	5	1	5	8	7	0	4	10/27/1992	Fulton et al.		252	309		07/25/1990
		F.C	5	1	6	7	7	1	6	12/01/1992	Boitnott et al.		118	719		09/28/1990
		F.D	5	1	6	9	2	9	6	12/08/1992	Wilden		417	395		03/10/1989
		F.E	5	1	6	9	4	0	8	12/08/1992	Biggerstaff et al.		29	25.01		01/26/1990
	F.F 5 1 7 4 9 1 7 12/29/1992 Monzyk 252 60 07/19/1991 F.G 5 1 8 5 0 5 8 02/09/1993 Cathey, Jr. 156 656 01/29/1991 F.H 5 1 8 5 2 9 6 02/09/1993 Morita et al. 437 229 04/24/1991															07/19/1991
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F.J 5 1 8 6 7 1 8 02/16/1993 Tepman et al. 29 25.01 04/15/1991														06/03/1991		
	F.J 5 1 8 6 5 9 4 02/16/1993 Toshima et al. 4 414 217 04/19/1990 F.J 5 1 8 6 7 1 8 02/16/1993 Tepman et al. 29 25.01 04/15/1991 F.K 5 1 8 8 5 1 5 02/23/1993 Horn 417 63 06/03/1991 FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS															
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1	<i>,</i> , ,	F.S	C.	к. С	Obe		al., ;	lmag			Supercritical Carbon Di			rials, Vol.	. 9, No. 1	i3, pp. 1039-1043,
	/	F,T	E.	M. I	Rus:	sick and	et a	ıl., <u>S</u> Ilutio	Super on Pr	critical Carbon evention, ACS	Dioxide Extraction of S Symposium Series, Vo	olvent fro I. 670, pp	m Micro-Mac . 255-269, O	chined St ctober 21	ructures,	, Supercritical Fluids
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	G.B		5	1	9	1	9	9	3	03/09/1993	Wanger et al.	******************	220	333		02/24/1992
	G.C	;	5	1	9	3	5	6	0	03/16/1993	Tanaka et al.		134	56 R		06/24/1991
	G.D		5	1	9	5	8	7	8	03/23/1993	Sahiavo et al.		417	393		05/20/1991
	G.E		5	1	9	6	1	3	4	03/23/1993	Jackson		252	103		08/17/1992
	G.F		5	2	0	1	9	6	0	04/13/1993	Starov		134	11		02/26/1992
	G.G		5 2	2	1	3	4	8	5	05/25/1993	Wilden		417	393		11/19/1991
	G.H		5 2	2	1	3	6	1	9	05/25/1993	Jackson et al.		134	1		11/30/1989
	G.I	1	5 2	2	1	5	5	9	2	06/01/1993	Jackson		134	1		01/22/1991
	G.J		5 2	2	1	7	0	4	3	06/08/1993	Novakovi *		137	460		02/24/1992
	G.K		5	2	2	1	0	1	9	06/22/1993	Pechacek et al.		220	315		11/07/1991
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	G.S						oerc 97.		al Flu	id Extraction:	Metals as Complexes, J	lournal of	Chromatogr	aphy A, \	/ol. 785,	pp. 369-383,
1	G.T	100	. Xı lero	ı e	t al. lizat	, <u>St</u>	and	icro I Py	n-Siz rolysi	ed Spherical \ s, Appl. Phys.	/ttrium Oxide Based Pho Lett., Vol. 71, No. 22, p	osphors F p. 1643-1	Prepared by \$ 645, Septem	Supercriti ber 22, 1	cal CO ₂ - 1997.	Assisted
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	H.C	5	2	2	5	1	7	3	07/06/1993	Wai		423	2		10/25/1991
	H.D	5	2	3	6	6	0	2	08/17/1996	Jackson		210	748		01/28/1991
	H.E	5	2	3	6	6	6	9	08/17/1993	Simmons et al-		422	113		05/08/1992
H.F 5 2 3 7 8 2 4 08/24/1993 Pawliszyn 62 51.1 02/16/1990 H.G 5 2 3 8 6 7 1 08/24/1993 Matson et al. 423 397 11/22/1988 H.H 5 2 4 0 3 9 0 08/31/1993 Kvinge et al. 417 393 03/27/1992															
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	H.S	Н.	Klei	in e	t al.,	Сус	oik	Organ	nic Carbonates	Serve as Solvents and	Reactive	Diluents, Co	oatings W	orld, pp	. 38-40, May 1997.
1	н.т	J. Vo	B0h 1. 36	ler o	et al.	, <u>Lir</u> pp.	139	Arra 91-13	y of Complem 98, May 1997.	entary Metal Oxide Sem	iconduct	or Double-Pa	ss Metal	Micro-m	irrors, Opt. Eng.
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	<u> </u>	I.B	5	2	6	1	9	6	5	11/16/1993	Moslehi			134	1		08/28/1992
		I.C	5	2	6	6	2	0	5	113-1003	Fulton et al.			210	639		07/01/1992
		I.D	5	2	6	7	4	5	5	12/07/1993	Dewees et al.		,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	68	5 C		07/13/1992
	 	I.E	5	2	6	9	8	1	5	12/14/1993	Schlenker et al.			8	475		11/13/1992
	<u> </u>	1.6	5	2	6	9	8	5	0	12/14/1993	Jackson			134	2		08/27/1990
		1.G	5	2	7	4	1	2	9	12/28/1993	Natale et al.			549	349		06/12/1991
	 	I.H	5	2	8	0	6	9	3	01/25/1994	Heudecker			53	306		10/07/1992
		1.1	5	2	8	5	3	5	2	02/08/1994	Pastore et al.			361	707		07/15/1992
1	-	1.J	5	2	8	8	3	3	3	02/22/1994	Tanaka et al.			134	31		07/29/1992
	/	I.K	5	2	9	0	3	6	1	03/01/1994	Hayashida et al.			134	2	_	01/23/1992
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		I.S				ain 20,			esign	of Nonionic S	urfactants for Supe	rcriti	cal Carbo	on Dioxide , \$	Science, '	Vol. 274,	pp. 2049-2052,
V		I.T	L.	Zna eatn	idi e neni	et al.	, <u>Ba</u> //g(0	tch OCH	and S	Semi-Continuo Materials Rese	ous Synthesis of Ma arch Bulletin, Vol. 3	gnes	sium Oxio o. 12, pp	<u>de Powders f</u> . 1527-1535,	rom Hydr Decemb	olysis an er 1996.	d Supercritical
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	J.B	5	2	9	8	0	3	2	03/29/1994	Schlenker et al.		8	475		08/08/1992
	J.C	5	3	0	4	5	1	5	04/19/1994	Morita et al.		437	231		08/07/1992
	J.D	5	3	0	6	3	5	0	04/26/1994	Hoy et al.		134	22.14		04/27/1992
	J.E	5	3	1	2	8	8	2	05/17/1994	DeSimone et al.		526	201		07/30/1993
	J.F	5	3	1	3	9	6	5	05/24/1994	Palen		134	61		06/01/1992
	J.G	5	3	1	4	5	7	4	05/24/1994	Takahashi		156	646		06/25/1993
	J.H	5	3	1	6	5	9	1	05/31/1994	Chao et al.		134	34		08/10/1992
	J.1	5	3	2	0	7	4	2	06/14/1994	Fletcher et al.		208	89		10/19/1992
	J.J	5	3	2	8	7	2	2	07/12/1994	Ghanayem et al.		427	250		11/06/1992
	J.K	5	3	3	4	3	3	2	08/02/1994	Lee		252	548		07/09/1992
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1	J.S	V.	G C	COU	rteci	uisse	e et 35, i	al., <u>K</u> No. 8	inetics of the , pp. 2539-254	Titanium Isopropoxide D 15, August 1996.	ecompo	sition In Supe	ercritical I	sopropyl	Al∞hol, Ind. Eng.
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	K.F	5	3	5	6	156	634		10/21/1991						
	K.G	645		08/04/1993											
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	K.I	5	3	7	0	7	4	0	12/06/1994		134	1		10/01/1993	
	K.J	5	3	7	0	7	4	1	12/06/1994	Bergman		134	3		11/18/1992
V	K.K	5	3	7	0	7	4	2	12/06/1994	Mitchell et al.		134	10		07/13/1992
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		L.B	5	4	0	1	3	2	2	03/28/1995	Marshall		134	13		06/30/1992
		L.C	5	4	0	3	6	2	1	04/04/1995	Jackson et al.		427	255.1		10/01/1993
		L.D	5	4	0	3	6	6	5	04/04/1995	Alley et al.		428	447		06/18/1993
		L.E	5	4	0	4	8	9	4	04/11/1995	Shiraiwa		134	66		05/18/1993
		L.F	5	4	1	2	9	5	8	05/09/1995	lliff et al.		68	5 C		12/06/1993
		L.G	5	4	1	7	7	6	8	05/23/1995	Smith, Jr. et al,		134	10		12/14/1993
		LH	5	4	3	3	3	3	4	07/18/1995	Reneau		220	319		09/08/1993
		L.I	5	4	4	7	2	9	4	09/05/1995	Sakata et al.		266	257		01/21/1994
	1	L.J	5	4	5	6	7	5	9	10/10/1995	Stanford, Jr. et al.		134	1		08/01/1994
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		M.D	5	4	9	4	5	2	6	02/27/1996	Paranjpe		134	1		05/04/1995
		M.E	5	5	0	0	0	8	1	03/19/1996	Bergman		156	646.1		12/05/1994
		M.F	5	5	0	1	7	6	1	03/26/1996	Evans et al.		156	344		10/18/1994
		M.G	5	5	0	3	1	7	6	04/02/1996	Dummire et al.		137	15		10/25/1994
	<u>.</u> ,	м.н	5	5	0	5	2	1	9	04/09/1996	Lansberry et al.		134	105		11/23/1994
		M.I	5	5	0	9	4	3	1	04/23/1996	Smith, Jr. et al.		134	95.1		11/14/1994
		M.J	5	5	1	4	2	2	0	05/07/1996	Wetmore et al.		134	22.18		12/09/1992
	/	M.K	5	5	2	2	9	3	8	06/04/1996	O'Brien		134	1		08/08/1994
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1		M.T	R.	D. <i>F</i>	Alle	n et	al., <u>l</u>	Perf	orma	nce Properties	s of Near-Monodisperse	Novolak	Resins, SPI	E, Vol. 24	38, pp. 2	250-260, June 1995.
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	N.B	5	5	3	3	5	3	8	07/09/1996	Marshall #		134	104.4		12/01/1994
	N.C	5	5	4	7	7	7	4	08/20/1996	Gimzewski et al.		428	694		09/01/1993
	N.D	5	5	5	0	2	1	1	08/27/1996	DeCrosta et al.		528	489		12/17/1992
	N.E	5	5	7	1	3	3	0	11/05/1996	Kyogoku		118	719		11/12/1993
	N.F	5	5	8	0	8	4	6	12/03/1996	Hayashida et al.		510	175		01/09/1995
	N.G 5 5 8 9 0 8 2 12/31/1996 Lin et al. 216 2 06/07/1995 N.H 5 5 8 9 1 0 5 12/31/1996 DeSimone et al. 252 351 05/18/1995														
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	N.J	5	6	2	1	34	203		10/27/1994						
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	N.S		B. J. 94.	ero	me e	et al.	., <u>S</u> y	nthe:	sis of New Lov	v-Dimensional Quatema	ry Comp	ounds, Ino	rg. Chem.	., Vol. 33	3, pp. 1733-1734,
7	N.T	J.	McH	larc	ly et	al.,	Pro	gress	in Supercritic	al CO, Cleaning, SAMPI	E Jour, V	ol. 29, No. 5	, pp. 20-2	7, Septe	ember 1993.
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U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. SUBSTITUTE FORM PTO-1449 PATENT AND TRADEMARK OFFICE **SSIT-114** (MODIFIED) INFORMATION DISCLOSURE APPLICANT STATEMENT BY APPLICANT Kawamura et al. (Use several sheets if necessary) FILING DATE September 29, 2004 (37 CFR 1.98(b)) **U.S. PATENT DOCUMENTS** ISSUE **EXAMINER PATENTEE CLASS** PATENT NUMBER DATE INITIAL 5 6 3 2 8 4 7 05/27/1997 Ohno et al. 156 O.A 6 5 06/03/1997 Muraoka 510 OB 5 3 4 6 3 134 6 5 08/10/1997 Schulz O.C 5 3 546 08/24/1997 O.D 5 6 4 1 8 8 Beckman et al. McDermott et al. 34 07/08/1997 5 6 4 5 5 O.E 417 07/22/1997 Stapelfeldt 6 O.F 4 9 8 0 9 134 08/12/1997 Olesen et al. 6 5 6 0 9 0.G 5 09/09/1997 430 6 6 5 2 7 Allen et al. O.H 5 5 09/23/1997 Townsend et al. 68 6 2 5 0.1 5 6 9 117 09/30/1997 Habuka 6 7 2 2 0 4 0.35 8 O.K 5 6 7 6 7 0 5 10/14/1997 Jureller et al. FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS COUNTRY OR **PUBLICATION** DOCUMENT CLASS DATE PATENT OFFICE NUMBER O.L O.M O.N 0.0 O.P O.Q OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) R. Purtell et al., Precision Parts Cleaning Using Supercritical Fluids, J. Vac. Sci. Technol. A., Vol. 11, No. 4, pp. 1696-1701, O.R MDA July 1993. E. Bok et al., Supercritical Fluids for Single Wafer Cleaning, Solid State Technology, pp. 117-120, June 1992 0.5 T. Adschiri et al., Rapid and Continuous Hydrothermal Crystallization of Metal Oxide Particles in Supercritical Water, J. Am. O.T Ceram. Cos., Vol. 75, No. 4, pp. 1019-1022, 1992. DATE CONSIDERED **EXAMINER** EXAMINER: Initial if citation considered, whether or not in conformance. Draw line through citation only if not in conformance and not considered. Include a copy of this form with next communication to Applicant.

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		P.B	5	6	\vdash	9	1	7	1	10/21/1997	Saga et al.		134	142		08/20/1996
	ļ	P.C	5	6	8	3	4	7	3	11/04/1997	Jureller et al.		8	286		03/06/1995
	 	P.D	5	6	8	3	9	7	7	11/04/1997	Jureller et al.		510			02/07/1997
		P.E	5	6	8	8	8	7	9	11/18/1997	DeSimone Biebl		526	89		02/14/1996
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MI		Q.A	5	7	3	0	8	7	4	03/24/1998	Wai et al.		210	638		06/02/1994
1 18		Q.B	5	7	3	6	4	2	5	04/07/1998	Smith et al.		438	778		11/14/1996
		Q.C	5	7	3	9	2	2	3	04/14/1998	DeSimone *		526	89		09/18/1995
		Q.D	5	7	4	6	0	0	8	05/05/1998	Yamashita et al.		34	211		02/24/1997
		Q.E	5	7	6	6	3	6	7	06/16/1998	Smith et al.	-	134	2		05/14/1996
	 	Q.F	5	7	6	9	5	8	8	06/23/1998	Toshima et al.		414	217		08/20/1996
	T	Q.G	5	7	8	3	0	8	2	07/21/1998	DeSimone et al.		210	634		11/03/1995
	1	Q.H	5	7	9	7	7	1	9	08/25/1998	James et al.		417	46		10/30/1996
		Q.i	5	7	9	8	1	2	6	08/25/1998	Fujikawa et al.*		425	78		05/21/1997
-		Q.J	5	7	9	8	4	3	8	08/25/1998	Sawan et al.		528	483		09/09/1996
	1	Q.K	5	8	0	4	6	0	7	09/08/1998	Hedrick et al.		521	64		10/16/1997
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		Q.S	D. 15	H. 2 85-1	ige 591	ret , O	al., j	Con er 1	pres 987.	sed Fluid Tecl	nnology: Application to F	RIE Deve	loped Resist	s, AIChE	Journal,	Vol. 33, No. 10, pp.
1		Q.T	D.	W. i	Mat	son Chei	et a	I., <u>F</u> Res.	lapid , Vol.	Expansion of 26, No. 11, pp	Supercritical Fluid Soluti 5. 2298-2306, 1987.	ions: Sol	ute Formation	n of Powo	lers, Thi	n Films, and Fibers,
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		R.C	5	8	4	7	4	4	3	12/08/1998	Cho et al.			257	632		11/14/1996
		R.D	5	8	6	6	0	0	5	02/02/1999	DeSimone et al.			210	634		11/01/1996
		R.E	5	8	6	8	8	5	6	02/09/1999	Douglas et al.			134	2		07/23/1997
		R.F	5	8	6	8	8	6		134	26		07/31/1997				
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		R.H	5	8	7	2	2	5		546	336		04/01/1997				
		R.I	5	8	7	3	9	4	8	02/23/1999			134	19		06/24/1997	
		R.J	5	8	8	1	5	7	7	03/16/199			68	5		09/09/1996	
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		R.S	<u>Fir</u>	nal F 87.	Rep	ort o	n th	e Sa	fety	Assessment o	f Propylene Carbon	ate,	J. Ameri	can College	of Toxicol	logy, Vol	. 6, No. 1, pp. 23-51,
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Sheet 19 (S) of 28 U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. SERIAL NO. SUBSTITUTE FORM PTO-1449 10/711,649 PATENT AND TRADEMARK OFFICE **SSIT-114** INFORMATION DISCLOSURE APPLICANT STATEMENT BY APPLICANT Kawamura et al. **GROUP** FILING DATE (Use several sheets if necessary) September 29, 2004 1756 U.S. PATENT DOCUMENTS FILING DATE ISSUE IF APPROPRIATE **SUBCLASS** PATENT NUMBER DATE **PATENTEE CLASS** 08/25/1998 46 417 5 8 8 8 0 5 ١٥ 03/30/1999 Fitzgerald et al. 08/26/1997 692 438 5 8 9 3 5 6 04/13/1999 Berman et al. 134 1.3 03/11/1997 04/27/1999 Huynh et al. 8 9 6 8 5 373 110 04/28/1997 04/27/1999 Fujikawa et al. 5 8 9 8 7 2 05/04/1999 Murphy et al. 156 359 09/11/1996 5 9 0 0 0 07/03/1997 Batchelder 430 395 05/04/1999 9 5 0 0 3 5 4 11/26/1997 8 158 9 7 3 05/18/1999 Preston et al. 5 0 4 02/10/1997 534 05/25/1999 427 5 9 0 6 8 6 ค Webb 2 10/16/1996 134 06/01/1999 McCullough et al. 9 0 8 5 0 5 10/21/1996 29 25.01 8 07/27/1999 **Jevtic** 9 2 8 3 9 5 06/14/1996 210 634 5 9 3 2 0 0 08/03/1999 Yager et al. FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **TRANSLATION COUNTRY OR PUBLICATION** DOCUMENT **SUBCLASS** (YES/NO) PATENT OFFICE **CLASS** NUMBER DATE OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

Kawakami et al., A Super Low-k(k=1.1) Silica Aerogel Film Using Supercritical Drying Technique, IEEE, pp. 143-145, 2000. MDIT S.R R. F. Reidy, Effects of Supercritical Processing on Ultra Low-k Films, Texas Advanced Technology Program, Texas S.S Instruments and the Texas Academy of Mathematics and Science Anthony Muscat, Backend Processing Using Supercritical CO2, University of Arizona S.T

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		T.J	╁	9	8	438	715		02/15/1995							
	1	T.K	5	9	8	9	3	4	2	11/23/1999	Ikede et al.		118	52		01/28/1997
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	U.B	5	9	9	4	6	9	6	11/30/1999	Tai et al.		250	288		01/27/1998
	U.C	6	0	0	5	2	2	6	12/21/1999	Aschner et al.		219	390		11/24/1997
	U.D	6	0	1	7	8	2	0	01/25/2000	Ting et al.		438	689		07/17/1998
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		V.D	6	0	7	7	3	2	1	06/20/2000	Adachi et al.		29	25.01		11/07/1997
		V.E	6	0	8	2	1	5	0	07/04/2000	Stucker		68	18 R		07/30/1999
		V.F	6	0	8	5	9	3	5	07/11/2000	Malchow et al.		220	813		08/10/1998
		V.G	6	0	9	7	0	1	5	08/01/2000	McCullough et al.		219	686		10/14/1998
		V.H	6	0	9	9	6	1	9	08/08/2000	Lansbarkis et al.		95	118		10/13/1998
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1 -	1	W.B	6	1	2	8	8	3	0	10/10/2000	Bettcher et al.		34	404		05/15/1999
	 	w.c	6	1	4	0	2	5	2	10/31/2000	Cho et al.		438	781	,,	05/05/1998
		W.D	6	1	4	5	5	1	9	11/14/2000	Konishi et al.		134	95.2		05/15/1997
	1	W.E	6	1	4	9	8	2	8	11/21/2000	Vaartstra		216	57		05/05/1997
		W.F	6	1	5	9	2	9	5	12/12/2000	Maskara et al.		118	688		04/22/1999
ļ		W.G	6	1	6	4	2	9	134	61	-	06/12/1998				
	 	W.H	6	1	7	1	427	96		07/15/1998						
-		W.I	6	1	8	6	7	2	414	217		02/24/1998				
		w.J	6	2	0	0	510	285		,05/27/1999						
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1		W.T	Ma Pu	sud blic	la e atio	t al., n Da	Pro	ces 1/0	s and 7/200	Apparatus fo 2, Filed 02/08	r Removing Residues fr /2002, U.S. Class 438/6	om the M	licrostructure	of an Ob	<u>ject,</u> US	2002/0164873 A1,
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	-	X.B	6	2	2	4	7	7	4	05/01/2001	DeSimor			210	634		02/12/1999
	 	X.C	6	2	2	8	5	6	3	05/08/2001	Starov et			430	327		09/17/1999
		X.D	6	2	2	8	8	2	6	05/08/2001	DeYoung	g et al.		510	291		10/18/1999
		X.E	6	2	3	2	2	3	8	05/15/2001	Chang et	t al.		438	725		02/08/1999
	<u> </u>	X.F	6	2	3	2	4	1	7	05/15/2001	et al.		526	171		09/12/1997	
		X.G	6	2	3	5	6	3	4	05/22/2001	al.		438	680		05/20/1998	
		X.H	6	2	3	9	0	3	8	05/29/2001	Wen			438	745		09/09/1996
		X.I	6	2	4	1	8	2	5	06/05/2001	Wytman			118	733		04/16/1999
		X.J	6	2	4	2	1	6	5	06/05/2001	Vaartstra	3		430	329		08/28/1998
\	1	X.K	6	2	4	4	1	2	1	06/12/2001	Hunter			73	865.9		03/06/1998
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Y.S Xu et al., Supercritical Fluid Cleaning of Semiconductor Substitutes, 05 2003/022525 Africal Fluid Cleaning of Semiconductor Substitutes, 05 2003/022525 Africal Fluid Cleaning Centrifugal Phase Shifting Separation Process and Apparatus, US 2003/0205510 A1, Publication Date 11/06/2003, Filed 03/13/2001, U.S. Class 210/86.

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Sheet 26 (Z) of 28

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		Z.B	6	3	4	4	1	7	4	02/05/2002	Miller et al.		422	98		04/12/1999
		Z.C	6	3	4	4	2	4	3	02/05/2002	McClain et al.		427	388.1		08/02/2001
		Z.D	6	3	5	5	0	7	2	03/12/2002	Racette et al.		8	142		10/15/1999
		Z.E	6	3	5	8	6	7	3	03/19/2002	Namatsu		430	311		09/03/1999
		Z.F	6	3	6	1	6	9	6	03/26/2002	Spiegelman et al.		210	662		01/19/2000
<u> </u>		Z.G	6	3	6	7	4	9	1	04/09/2002	Marshall et al.		134	104.4		09/15/2000
		Z.H	6	3	8	0	1	0	5	04/30/2022	Smith et al.		438	778		06/02/1999
	 	Z.I	6	3	8	8	3	1	7	05/14/2002	Reese		257	713		09/25/2000
		Z.J	6	3	8	9	6	7	7	05/21/2002	Lenz		29	559		08/30/2001
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	<u>); </u>	AA.B	6	4	3	6	8	2	4	08/20/2002	Chool et al.		438	687		07/02/1999
		AA.C	6	4	5	╫	5	1	0	09/17/2002	Messick et al.		430	311		02/21/2001
		AA.D	6	4	5	4	5	1	9	09/24/2002	Toshima et al.		414	805	·	03/07/1997
ļ		AA.E	6	4	5	4	9	4	5	09/24/2002	Weigl et al.	-	210	634		11/01/2000
 		AA,F	6	4	5	4	9	4	5	09/24/2002	Weigl et al.		210	634		11/01/2000
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Sheet 28 (BB) of 28

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7	•	BB.B	6	5	5	8	4	7	5	05/06/2003	Jur et al.		134	21		04/10/2000
		BB.C	6	5	6	1	2	1	3	05/13/2003	Wang et al.		137	263		06/05/2001
		BB.D	6	5	6	1	2	2	0	05/13/2003	McCullough et al.		137	565.12		04/23/2001
		88.E	6	5	6	1	4	8	1	05/13/2003	Filonczuk		251	129.12		08/13/2001
		BB.F	6	5	6	1	7	6	7	05/13/2003	Berger et al.		417	53		08/01/2001
		BB.G	6	5	6	2	1	4	6	05/13/2003	DeYoung et al.		134	30	•	08/17/2001
		вв.н	6	5	6	4	8	2	6	05/20/2003	Shen		137	505.18		07/24/2001
		BB.I	6	5	7	6	1	3	8	06/10/2003	Sateria et al.		210	664		12/14/2000
		B8.J	6	5	8	3	0	6	7	06/24/2003	Chang et al.		438	723		07/03/2001
4	/	BB.K	6	6	2	3	3	5	5	09/23/2003	McClain et al.		457	60		03/23/2001
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Sheet 2 (B) of 14

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Sheet 5 (E) of 14

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Sheet 6 (F) of 14

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Sheet 7 (G) of 14 ATTY. DOCKET NO. SERIAL NO. SUBSTITUTE FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE 10/711,649 PATENT AND TRADEMARK OFFICE (MODIFIED) **SSIT-114** APPLICANT INFORMATION DISCLOSURE STATEMENT BY APPLICANT Kawamura et al. **GROUP** FILING DATE (Use several sheets if necessary) September 29, 2004 1756 (37 CFR 1.98(b)) **U.S. PATENT DOCUMENTS** FILING DATE **EXAMINER** ISSUE IF APPROPRIATE **SUBCLASS** INITIAL PATENT NUMBER DATE **PATENTEE CLASS** G.A G.B G.C G.D G.E G.F G.G G.H á G.I G.JG.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **PUBLICATION COUNTRY OR TRANSLATION** DOCUMENT SUBCLASS (YES/NO) PATENT OFFICE **CLASS** DATE NUMBER MAIT H01L 21/302 **Abstract Only** 08/21/1990 Japan JP 2-209729 G.L 21/56 **Abstract Only** 12/18/1990 Japan HO1L G.M JP 2-304941 021/027 **Abstract Only** H01L G.N JP 7-142333 06/02/1995 Japan H01L 21/56 **Abstract Only** JP 8-186140 A 07/16/1996 Japan G.O H01L 021/027 **Abstract Only** G.P JP 8-222508 A 08/30/1996 Japan 21/68 H01L **Abstract Only** G.Q JP 10-144757 A 05/29/1998 Japan OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) G.R G.S

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Sheet 8 (H) of 14

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Sheet 9 (I) of 14

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Sheet 10 (J) of 14 ATTY, DOCKET NO. SERIAL NO. **SUBSTITUTE FORM PTO-1449** U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE **SSIT-114** 10/711,649 (MODIFIED) APPLICANT INFORMATION DISCLOSURE Kawamura et al. STATEMENT BY APPLICANT **GROUP** (Use several sheets if necessary) FILING DATE September 29, 2004 1756 (37 CFR 1.98(b)) **U.S. PATENT DOCUMENTS** FILING DATE ISSUE EXAMINER IF APPROPRIATE **PATENTEE** CLASS SUBCLASS PATENT NUMBER DATE INITIAL J.A J.B J.C J.D J.E J.F J.G J.H J.I J.J J.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **TRANSLATION** COUNTRY OR **PUBLICATION** DOCUMENT SUBCLASS (YES/NO) CLASS PATENT OFFICE NUMBER DATE MNt C23C 16/00 PCT 12/03/1987 J.L WO 87/07309 B08B 7/00 06/14/1990 PCT J.M WO 90/06189 3/00 **Abstract Only** C22B **PCT** WO 90/13675 11/15/1990 J.N 21/00 H01L J.O WO 91/12629 A 08/22/1991 **PCT Abstract Only** PCT D06B 5/16 07/22/1993 WO 93/14255 J.P 11/76 Abstract Only **PCT D06M** 07/22/1993 WO 93/14259 J.Q OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) J.R J.S

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Sheet 11 (K) of 14

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DATE CONSIDERED 3/3/06 EXAMINER: Initial if citation considered, whether or not in conformance. Draw line through citation only if not in conformance and not considered. Include a copy of this form with next communication to Applicant.

**EXAMINER** 

Sheet 14 (N) of 14 U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. SERIAL NO. **SUBSTITUTE FORM PTO-1449** 10/711,649 (MODIFIED) PATENT AND TRADEMARK OFFICE **SSIT-114 APPLICANT** INFORMATION DISCLOSURE STATEMENT BY APPLICANT Kawamura et al. **GROUP** FILING DATE (Use several sheets if necessary) September 29, 2004 1756 (37 CFR 1.98(b)) U.S. PATENT DOCUMENTS FILING DATE ISSUE **EXAMINER** IF APPROPRIATE **SUBCLASS** PATENT NUMBER DATE PATENTEE **CLASS** INITIAL N.A N.B N.C N.D N.E N.F N.G N.H N.I N.J N.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **TRANSLATION COUNTRY OR PUBLICATION** DOCUMENT (YES/NO) PATENT OFFICE **CLASS SUBCLASS** DATE NUMBER PCT H01L MBH 10/04/2003 WO 03/030219 A2 N.L N.M N.N N.O N.P . . N.Q OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) N.R

N.S

N.T

EXAMINER

DATE CONSIDERED

3/3/6

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## **ELECTRONIC INFORMATION DISĆLOSURE STATEMENT**

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

A METHOD FOR SUPERCRITICAL CARBON DIOXIDE PROCESSING OF FLUORO-CARBON FILMS

**Application Number:** 

10/711649

Confirmation Number:

5648

First Named Applicant:

Kohei Kawamura

Attorney Docket Number:

SSIT-114

Art Unit:

1756

Examiner:

Search string:

( 6485895 or 6486078 or 6492090 or 6500605 or 6508259 or 6509136 or 6521466 or 6537916 or 6541278 or 6546946 or 6550484 or 6635582 or 6641678 or 6656666 or 6669916 or 6673521 or 6677244 or 6685903 or 6737725 or 6764552 or 6777312

or 6780765).pn

## **US Patent Documents**

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
MXX	1	6485895	2002-11-26	Choi et al.	B1	430	330
	2	6486078	2002-11-26	Rangarajan et al.	B1	438	778
	3	6492090	2002-12-10	Nishi et al.	B2	430	270.1
	4	6500605	2002-12-31	Mullee et al.	B1	430	329
H	5	6508259	2003-01-21	Tseronis et al.	B1	134	105
	6	6509136	2003-01-21	Goldfarb et al.	B1	430	272.1
	7	6521466	2003-02-18	Castrucci	B1	438	5
	8	6537916	2003-03-25	Mullee et al.	B2	438	692
	9	6541278	2003-04-01	Morita et al.	B2	438	3
	10	6546946	2003-04-15	Dunmire	B2	137	15.18
	11	6550484	2003-04-22	Gopjnath et al.	B1	134	1.2
	12	6635582	2003-10-21	Yun et al.	B2	438	745
	13	6641678	2003-11-04	DeYoung et al.	B2	134	36
	14	6656666	2003-12-02	Simons et al.	B2	430	322
	15	6669916	2003-12-30	Heim et al.	B2	423	245.1
1	16	6673521	2004-01-06	Moreau et al.	B2	430	315
	17	6677244	2004-01-13	Ono et al.	B2	438	706
	18	6685903	2004-02-03	Wong et al.	B2	423	262
	19	6737725	2004-05-18	Grill et al.	B2	257	522
H	20	6764552	2004-07-20	Joyce et al.	B1	134	3
1	21	6777312	2004-08-17	Yang et al.	B2	438	464

NA	22	6780765	2004-08-24	Goldstein	B2	438	660	

## Remarks

Note: Remarks are not for responding to an office action.

In accordance with the duty of candor and good faith imposed by 37 CFR 1.56 and means of complying therewith according to 37 CFR 1.97 and 1.98, the references listed in this Supplemental Information Disclosure Statement are called to the attention of the United States Patent and Trademark Office in connection with the above-identified patent application. No admission is made that the cited art represents the prior art or that the cited art is the most material art. In accordance with 37 CFR 1.97(b), this Supplemental Information Disclosure Statement shall be considered because it is filed before the mailing date of a first Office Action on the merits. The Examiner is urged to consider all the cited references and to make an independent decision with respect to their materiality. Applicants believe no fee is due in connection with the filing of this paper. If any additional fees are necessary to complete this communication, please apply them to Deposit Account No. 23-3000.

## **Signature**

Examiner Name	Date
M gries O. plann	3/3/06